

Form PTO-144		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1114		SERIAL NO. 09/233,377	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					FILING DATE January 18, 1999		GROUP 2813	

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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
TSP	AA	4,378,628	04-1983	Levinstein et al.			
TSP	AB	6,054,387	04-2000	Fukuda			
	AC						
	AD						
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	AG						
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					Yes	No	
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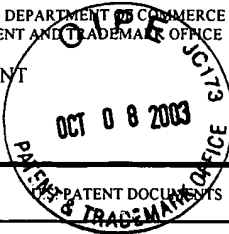
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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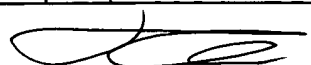
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1114	SERIAL NO. 09/233,377
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Gurtej S. Sandhu et al.	
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BP	AA	4,337,476	06-1982	Fraser et al.		
	AB					
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FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
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